

# Wrap up: Issues Addressed

- **Tracks towards nanocomputing**
  - ◆ Top Down (More Moore) — Shrinking CMOS technology
  - ◆ Bottom up (Beyond Moore) — Self-assembling nano elements
  
- **Fault categories**
  - ◆ Soft errors
  - ◆ Design faults
  - ◆ Attacks taking advantage of hardware vulnerabilities
  - ◆ New fault models induced by emerging nanoscale technologies
  
- **Dependability enhancement techniques**
  - ◆ Built-in self test
  - ◆ Asynchronous design
  - ◆ Signature analysis of data flow
  - ◆ Checkpointing and Rollback
  - ◆ On-line diagnosis and reconfiguration in multicore systems

# Wrap up: What is Next?

- Increased concern about hardware impact on dependability and security — actual in DSN this year
- Workshop well-attended
- Comprehensive coverage
- Start of building up a community and forum
  - > Improve industrial participation
  - > Investigate possible connection with IEEE Int. On-Line Testing Symp.
  - > Extend bottom-up track

**Stay Tuned!**

